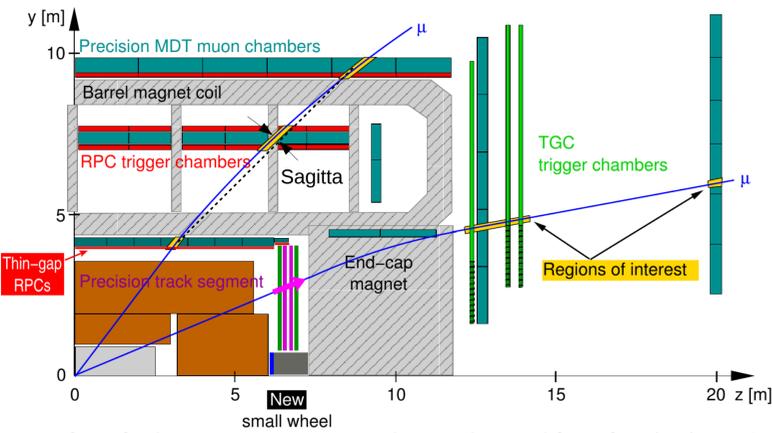


Motivation

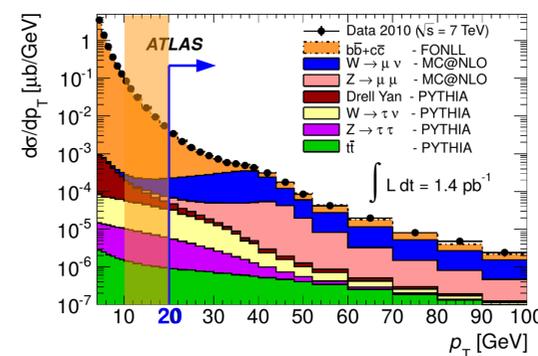
Muon trigger at the HL-LHC



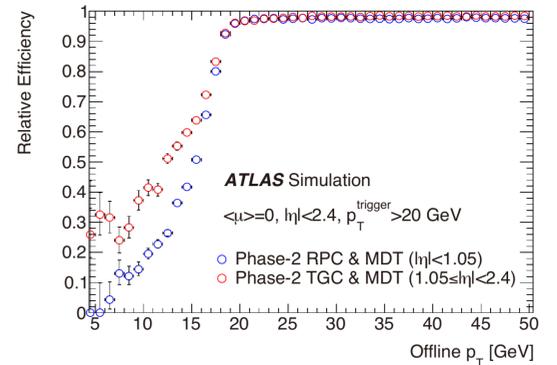
- ◆ 2-level trigger system: Hardware based level 0 (L0), software based high-level trigger (HLT).
- ◆ L0 muon trigger:
 - ◆ Pretrigger: Coincidence of RPC or TGC hits.
 - pp collision time (BCID) + η and ϕ position of the muon (spatial region of interest (ROI)).
 - p_T measurement with low resolution.
 - ◆ Final trigger: Use of precision hits of monitored drift-tube (MDT) chambers for precise p_T measurement.

L0 muon trigger efficiency and trigger rate

Inclusive muon spectrum



Trigger turn-on curve with respect to pretriggers

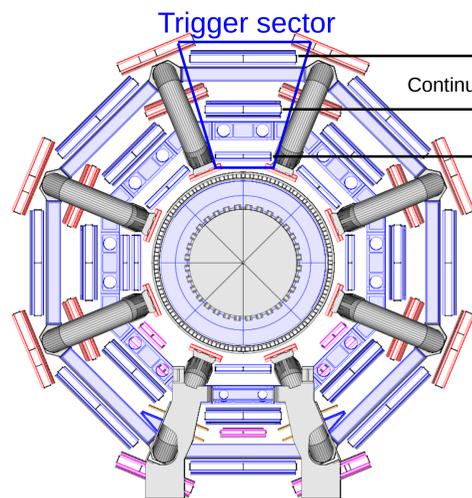


- ◆ The interesting electroweak physics is mainly at $p_T > 20$ GeV.
- ◆ The inclusive muon cross section is very steeply rising with decreasing p_T .
- ◆ Muon pretrigger without MDT data accepts a lot of muons with $10 \text{ GeV} < p_T < 20 \text{ GeV}$.
 - Reduction of the trigger rate due to sharpening of the turn-on curve and the rejection of accidental pretriggers:

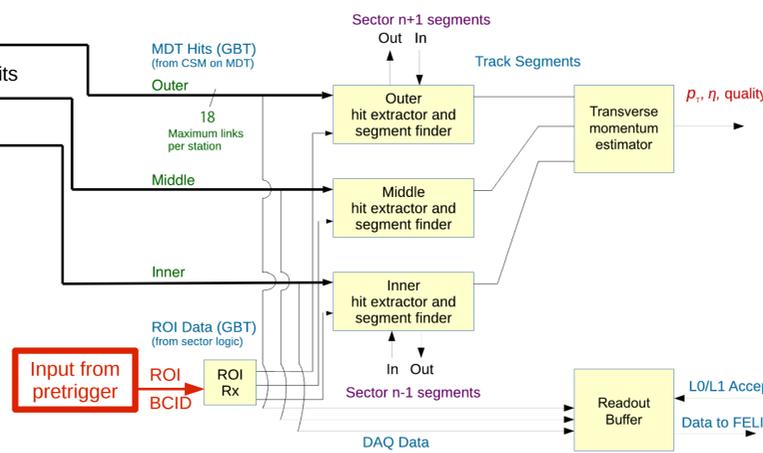
	Rate without MDTs	Rate with MDTs
Barrel ($ \eta < 1.05$)	45-85 kHz	~15 kHz
End caps ($1.05 < \eta < 2.4$)	15-20 kHz	~10 kHz

MDT trigger data flow

Segmentation of the MDT trigger



Data flow



Processing steps on the MDT trigger blade

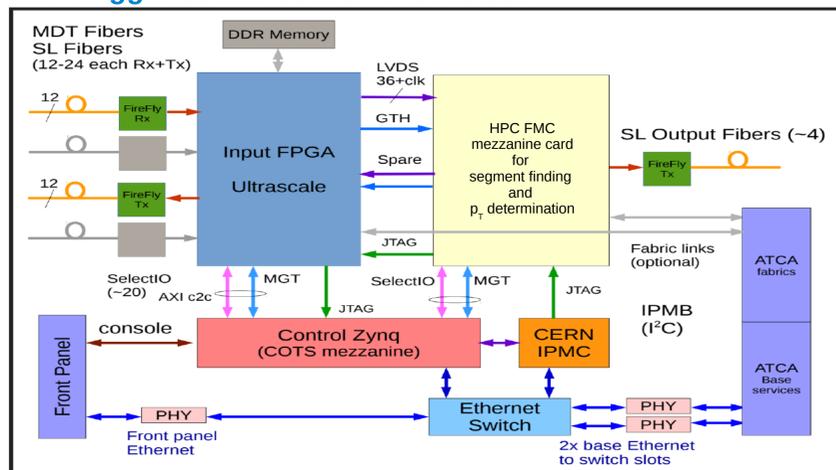
- ◆ Buffering of MDT hits.
- ◆ Selection of hits in the ROI which are compatible with the BCID.
- ◆ Conversion of hit times into drift radii.
- ◆ Track segment reconstruction in each chamber.
- ◆ Computation of sagitta from segment positions.
- ◆ Conversion of the sagitta into p_T .
- ◆ Sending of p_T to muon sector logic.

L0 muon trigger latency: $< 4.2 \mu\text{s}$

- ◆ MDT data of one trigger sector processed on one ATCA blade.
- ◆ Number of trigger sectors: 32 (barrel) + 32 (end caps) = 64.
 - 64 MDT trigger processor blades.

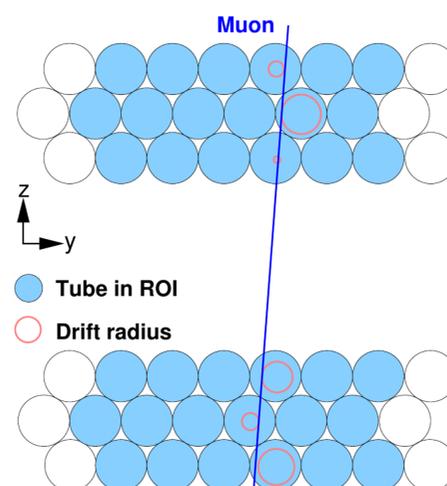
MDT trigger demonstrator blade

MDT trigger demonstrator ATCA blade



- ◆ MDT trigger demonstrator blade in preparation for end of 2018.
- ◆ Segment finding and p_T determination on a mezzanine card to study two different segment finding approaches:
 - ◆ Pattern recognition and segment fitting on an FPGA;
 - ◆ Pattern recognition on an associative memory chip, segment fitting on an FPGA.
- ◆ Use an FPGA with an embedded microprocessor to profit from its floating point precision for the p_T determination.

Segment finding strategies for the FPGA option



- ◆ Track segments are straight within a muon chamber:

$$y = a \cdot z + b$$
 - Two unknowns: slope a , intercept b .
- ◆ r : Drift radius. (y_w, z_w) : Wire position.

$$r = \frac{|y_w - a \cdot z_w - b|}{\sqrt{1 + a^2}} \Rightarrow b = \pm r \sqrt{1 + a^2} - (a * z_w - y_w)$$

- ◆ Option 1: 1-D approach (conceptual description)
 - ◆ Use seed value for a provided by trigger chambers.
 - ◆ Compute b for all hits and histogram them.
 - ◆ Find the maximum of this histogram and refit the hits in the maximum to get precise values for a and b and a goodness-of-fit estimator.
- ◆ Option 2: 2-D approach (conceptual description)
 - ◆ Compute b for all hits and several values of a around the seed value from the trigger chambers and histogram b separately for the chosen values of a .
 - ◆ Find the maximum of this 2-D histogram to get values for a and b . Optionally refit the hits in the maximum to get a goodness-of-fit estimator.

- ◆ Main advantage of the 1-D approach: Lightweight, FPGA resource saving.
- ◆ Main advantages of the 2-D approach: Faster than the 1-D approach if one drops the goodness-of-fit estimation, but high FPGA resource consumption.